

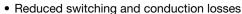
18N50G-TF1-T-VB Datasheet N-Channel 650 V (D-S) Super Junction Power MOSFET

PRODUCT SUMMA	RY	
V _{DS} (V) at T _J max.	650)
R _{DS(on)} at 25 °C (Ω)	V _{GS} = 10 V	0.19
Q _g Typ. (nC)	106	3
Q _{gs} (nC)	14	
Q _{gd} (nC)	33	
Configuration	Sing	le

FEATURES



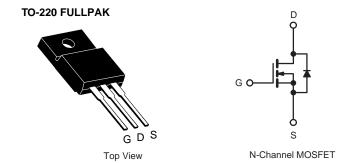




- Ultra low gate charge (Q_a)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial



ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	650	V	
Gate-Source Voltage			V_{GS}	± 30	7	
Continuous Drain Current (T _J = 150 °C)	V _{GS} at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	- I _D	20		
	VGS at 10 V	T _C = 100 °C		13	A	
Pulsed Drain Current ^a			I _{DM}	53		
Linear Derating Factor				1.67/1.5/0.3	W/°C	
Single Pulse Avalanche Energy b			E _{AS}	360	mJ	
Maximum Power Dissipation			P_{D}	200	W	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Drain-Source Voltage Slope	T _J = 125 °C		-1\//-1+	50	\//r	
Reverse Diode dV/dt ^d	•		dV/dt	3.1	- V/ns	
Soldering Recommendations (Peak Temperature) c	for	10 s		300	°C	

- a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD}=50$ V, starting $T_J=25$ °C, L=28.2 mH, $R_g=25$ Ω , $I_{AS}=4.5$ A. c. 1.6 mm from case. d. $I_{SD} \le I_D$, dI/dt=100 A/µs, starting $T_J=25$ °C.



THERMAL RESISTANCE RATI	NGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	°C/W
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.5	C/VV

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		•					
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.67	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2	-	5	V
		V _{GS} = ± 20 V		-	-	± 100	nA
Gate-Source Leakage	I _{GSS}	,	$V_{GS} = \pm 30 \text{ V}$	-	-	± 1	μA
Zawa Cata Valtana Duain Commant		V _{DS} =	= 520 V, V _{GS} = 0 V	-	-	1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 520 V	/, V _{GS} = 0 V, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 11 A	-	0.19	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 30 V, I _D = 11 A	-	7.0	-	S
Dynamic							
Input Capacitance	C _{iss}		V _{GS} = 0 V,	-	2322	-	
Output Capacitance	C _{oss}		$V_{DS} = 100 \text{ V},$		105	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1 MHz		-	4	-	
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	$V_{DS} = 0 V \text{ to } 520 V, V_{GS} = 0 V$		-	84	-	
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	293	-	
Total Gate Charge	Qg			-	71	106	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$	$I_D = 11 A, V_{DS} = 520 V$	-	14	-	nC
Gate-Drain Charge	Q_{gd}			-	33	-	
Turn-On Delay Time	t _{d(on)}	V _{DD} = 520 V, I _D = 11 A,		-	22	44	ns
Rise Time	t _r			-	34	68	
Turn-Off Delay Time	t _{d(off)}	V _{GS} =	$V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$		68	102	
Fall Time	t _f	1		-	42	84	
Gate Input Resistance	R _g	f = 1 MHz, open drain		-	0.78	-	Ω
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	21	
Pulsed Diode Forward Current	I _{SM}			-	-	53	A
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V		-	0.9	1.2	V
Reverse Recovery Time	t _{rr}			-	160	-	ns
Reverse Recovery Charge	Q _{rr}	$T_J = 25 \text{ °C, I}_F = I_S = 11 \text{ A,}$ $dI/dt = 100 \text{ A/}\mu\text{s, V}_R = 25 \text{ V}$		-	1.2	-	μC
Reverse Recovery Current	I _{RRM}			-	14	_	A

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

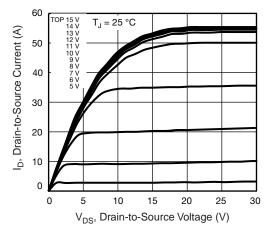


Fig. 1 - Typical Output Characteristics

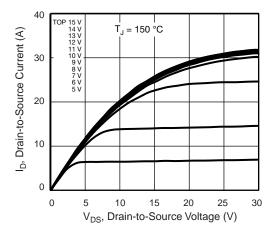


Fig. 2 - Typical Output Characteristics

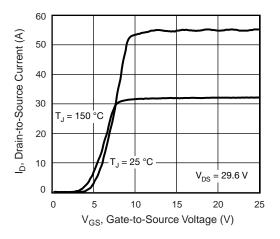


Fig. 3 - Typical Transfer Characteristics

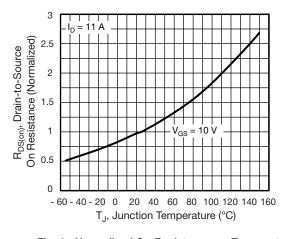


Fig. 4 - Normalized On-Resistance vs. Temperature

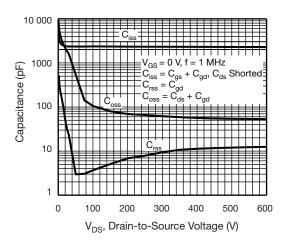


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

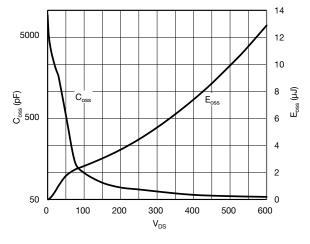


Fig. 6 - Coss and Eoss vs. VDS



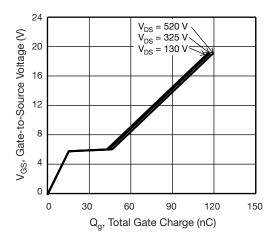


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

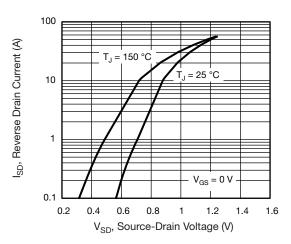


Fig. 8 - Typical Source-Drain Diode Forward Voltage

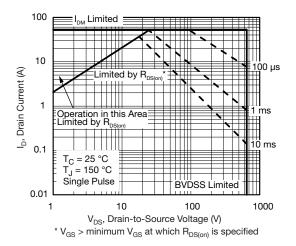


Fig. 9 - Maximum Safe Operating Area

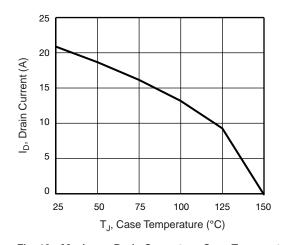


Fig. 10 - Maximum Drain Current vs. Case Temperature

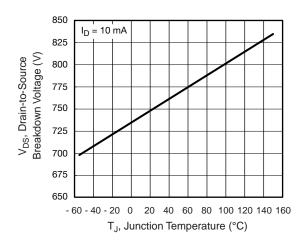


Fig. 11 - Temperature vs. Drain-to-Source Voltage



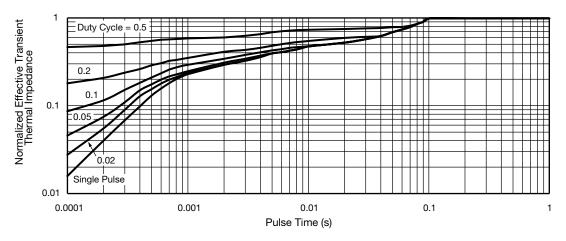


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

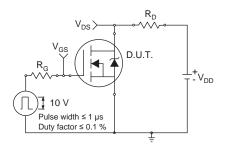


Fig. 13 - Switching Time Test Circuit

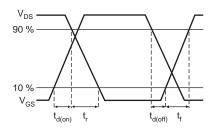


Fig. 14 - Switching Time Waveforms

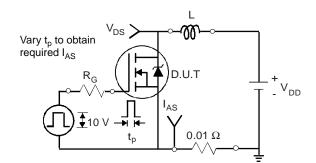


Fig. 15 - Unclamped Inductive Test Circuit

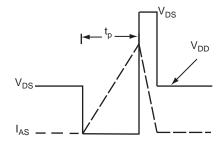


Fig. 16 - Unclamped Inductive Waveforms

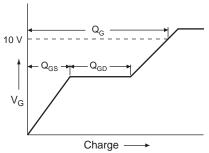


Fig. 17 - Basic Gate Charge Waveform

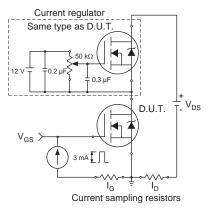
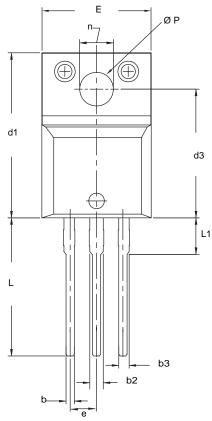
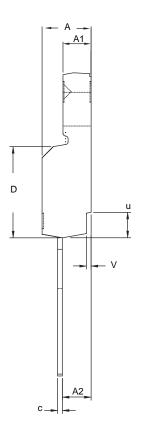


Fig. 18 - Gate Charge Test Circuit



TO-220 FULLPAK (HIGH VOLTAGE)





DIM.	MILLIN	METERS	MIN.	HES
	MIN.	MAX.		MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100	BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

- To be used only for process drawing.
 These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
 All critical dimensions should C meet C_{pk} > 1.33.
 All dimensions include burrs and plating thickness.
 No chipping or package damage.



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